Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/768,650	NAKANISHI ET AL.
Examiner	Art Unit

3748

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SEARCHED						
Class	Subclass	Date	Examiner			
60	274	05/24/05	RST			
	275					
	286					
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422	186.03	05/24/05	185			
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INTERFERENCE SEARCHED						
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
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